

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/518,736	HENDRIKS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,130,129 A	10-2000	Chen, Bin-Shing	438/257
*	B	US-6,323,516 B1	11-2001	Wang et al.	257/317
*	C	US-6,376,877 B1	04-2002	Yu et al.	257/317
*	D	US-6,413,809 B2	07-2002	Nakamura et al.	438/201
*	E	US-6,448,606 B1	09-2002	Yu et al.	257/315
*	F	US-6,562,681 B2	05-2003	Tuan et al.	438/257
*	G	US-6,566,196 B1	05-2003	Haselden et al.	438/257
*	H	US-6,570,215 B2	05-2003	Tuan et al.	257/315
*	I	US-6,559,008 B2	05-2003	Rabkin et al.	438/257
*	J	US-6,583,009 B1	06-2003	Hui et al.	438/264
*	K	US-6,743,675 B2	06-2004	Ding, Yi	438/257
*	L	US-6,777,741 B2	08-2004	Rabkin et al.	257/315
*	M	US-6,791,142 B2	09-2004	Tseng, Horng-Huei	257/316

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,844,586 B2	01-2005	Ding, Yi	257/315
*	B	US-6,838,342 B1	01-2005	Ding, Yi	438/257
*	C	US-6,846,712 B2	01-2005	Ding, Yi	438/257
*	D	US-6,885,044 B2	04-2005	Ding, Yi	257/202
*	E	US-6,893,921 B2	05-2005	Ding, Yi	438/259
*	F	US-6,902,974 B2	06-2005	Ding, Yi	438/257
*	G	US-6,951,782 B2	10-2005	Ding, Yi	438/137
*	H	US-2005/0224860 A1	10-2005	Hendriks et al.	257/315
*	I	US-6,962,851 B2	11-2005	Ding, Yi	438/266
*	J	US-6,962,852 B2	11-2005	Ding, Yi	438/267
*	K	US-6,974,739 B2	12-2005	Ding, Yi	438/201
*	L	US-6,995,060 B2	02-2006	Ding, Yi	438/257
*	M	US-7,018,895 B2	03-2006	Ding, Yi	438/257

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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	W	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,053,438 B2	05-2006	Ding, Yi	257/314
*	B	US-7,052,947 B2	05-2006	Ding, Yi	438/211
*	C	US-7,060,565 B2	06-2006	Ding, Yi	438/267
*	D	US-7,071,538 B1	07-2006	Shiraiwa et al.	257/635
*	E	US-7,091,091 B2	08-2006	Ding, Yi	438/265
*	F	US-7,101,757 B2	09-2006	Ding, Yi	438/257
*	G	US-7,153,742 B2	12-2006	Choi, Tae Ho	438/257
*	H	US-7,148,104 B2	12-2006	Ding, Yi	438/257
*	I	US-7,169,667 B2	01-2007	Ding, Yi	438/257
*	J	US-7,195,964 B2	03-2007	Ding, Yi	438/201
*	K	US-7,190,019 B2	03-2007	Ding, Yi	257/315
*	L	US-7,205,602 B2	04-2007	Hsieh, Chia-Ta	257/315
*	M	US-7,214,585 B2	05-2007	Ding, Yi	438/257

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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